Test Evolution Corporation

Evolving Technology for Test

A Company Overview
Providing engineering services, test instruments, sub-systems and systems in open standard formats in order to quickly provide low cost test solutions for R&D and manufacturing.

Test Evolution is a privately funded ATE technology development company founded and operated by Lev Alperovich and David Oka, both ex-founders of StepTech. Before selling StepTech to LTX, they partnered with ATE companies such as Teradyne, Credence and LTX providing engineering services ranging from the design of test instrumentation to the X family of testers for LTX. Over the past 30 years, they have successfully designed ATE test systems and instruments along with building and managing a profitable test business.

TEV specializes in providing all ranges of engineering services with expertise in digital pins and RF instrumentation. Reduce your R&D overhead and time to market by contracting with TEV engineering services.

Test Evolution is offering a unique way of developing OEM ATE technology. They will provide the engineering expertise to develop test instruments, sub-systems and systems in an open standard format and then allow an ATE provider, system integrator, semi-test house or a silicon vendor to develop, manufacture, rebrand and/or sell the ATE solution through a licensing agreement with TEV.

Outsource Engineering Markets

- ATE providers
- System integrators
- Semi-test houses
- Silicon vendors
- In-house test departments

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The products and services we offer are:

- Test instruments
  - SOC, mixed signal, RF systems
- Sub-systems
- Full systems such as the MS tester
- “Add-ons” and “Up-grades” to existing test equipment

Test Evolution will either license or OEM to ATE providers and semi-test houses.

Test Evolution can also help Silicon Vendor (SiV) in-house test departments and system integrators by providing custom solutions branded based on their unique test requirements. They can augment existing test systems or offer lower cost product offerings for addressing mainstream markets like:

- SOC
- RF
- Automotive
- CIS
- LCD drivers
- Flash

Test Evolution works with open standards to develop the ATE solutions. They include but are not limited to:

- PXI format
- ATCA format
- NI format

A prime example of an open architecture test head

- PXI & AXIe standard card formats
  - Air cooled test head
- Two configurations
  - Large: 28 ATCA slots, 20 PXI
- RF and AC instruments
  - PXI configured
  - COAX connection to DUT site
- Digital and DC instruments
  - AXIe configured
  - PXI express switched fabric
  - 10 MHz and 100 MHz clocks
  - Star triggering
  - Analog and calibration bus
  - Rear panel DUT connections
- Power management/automotive system
- Flash memory system

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- ATCA-based dynamic digital pins
  - Based upon ADI chip set
  - 48 channels/card
  - 100 MHz base vector rate
  - 400 MBits max; 800 MBits max (multiplexed)
  - 40 pS timing resolution
  - Period, timing and format on-the-fly
  - -2 V to +6.0 V output range with +12 V super voltage
  - 16/32/64 M vectors pattern memory
  - 64 M per channel capture and send memory

- S/W operating system
  - Based on visual studio C++ interface
  - Support for standard test languages
  - Multi-site support
  - Production maintenance tools
    - Calibration and checkers
  - Third party software is natively supported

- ATCA-based device power source
  - 12 channels
  - -22 v to +24 v; 1.2 A

- PXI-based RF source/measure unit
  - 10 MHz to 6 GHz source/measure